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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of: Robert J. SMALL et al.

Confirmation No: 5914

Application No.: 10/690,626

Art Unit: 1755

Filed: October 23 2003

Examiner:

For: **PARTICULATE OR PARTICLE-BOUND
CHELATING AGENTS**

Atty Docket No.: 060937-217-US

INFORMATION DISCLOSURE STATEMENT

U.S. Patent and Trademark Office
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Sir:

In accordance with the duty of disclosure provisions of 37 C.F.R. §1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the application.

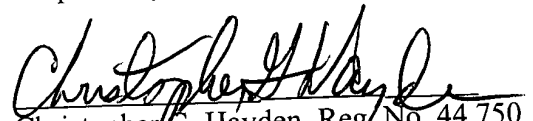
Enclosed with this Information Disclosure Statement is a list of all patents, publications, applications, or other information submitted for consideration by the Office. There are fifty-four (54) references listed in the above-referenced application; no U.S. references are submitted, however, the seven (7) foreign references, and one (1) article are submitted herewith. Remaining references can be provided upon request.

No fee is believed to be due for this submission, since this Information Disclosure Statement is being submitted before the first Office Action. Should any fees be required, however, please charge the required fees to Morgan, Lewis & Bockius LLP Deposit Account No. 50-0310.

Respectfully submitted,

September 13, 2004

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LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

ATTY DOCKET NO.

060937-0217

APPLICATION NO

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APPLICANT

Robert J. SMALL et al.

FILING DATE

October 24, 2003

GROUP

1755

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	A01	4,752,628	06/1988	Payne			
	A02	4,867,757	09/1989	Payne			
	A03	5,123,958	06/1992	Wiand			
	A04	5,334,332	08/1994	Lee			
	A05	5,352,277	10/1994	Sasaki			
	A06	5,417,877	05/1995	Ward			
	A07	5,429,708	07/1995	Linford et al.			
	A08	5,447,603	09/1995	Michalowski et al.			
	A09	5,482,566	01/1996	Lee			
	A10	5,489,233	02/1996	Cook et al.			
	A11	5,498,565	03/1996	Gocho et al.			
	A12	5,672,577	09/1997	Lee			
	A13	5,721,173	02/1998	Yano et al.			
	A14	5,750,070	05/1998	Tang et al.			
	A15	5,860,848	01/1999	Loncki et al.			
	A16	5,876,490	03/1999	Ronay			
	A17	5,902,780	05/1999	Lee			
	A18	5,938,505	08/1999	Morrison et al.			
	A19	5,958,794	09/1999	Bruxvoort et al.			
	A20	5,981,454	11/1999	Small			
	A21	5,991,835	11/1999	Mashimo et al.			
	A22	6,000,411	12/1999	Lee			
	A23	6,019,806	02/2000	Sees et al.			
	A24	6,099,604	08/2000	Sandhu et al.			
	A25	6,110,881	08/2000	Lee et al.			
	A26	6,117,220	09/2000	Kodama et al.			
	A27	6,117,775	09/2000	Kondo et al.			
	A28	6,117,783	09/2000	Small et al.			
	A29	6,121,217	09/2000	Lee			
	A30	6,132,637	10/2000	Hosali et al.			
	A31	6,140,287	10/2000	Lee			
	A32	6,156,661	12/2000	Small			
	A33	6,171,352	01/2001	Lee et al.			

	A34	6,187,730	02/2001	Lee			
	A35	6,221,818	04/2001	Lee			
	A36	6,276,372	08/2001	Lee			
	A37	6,303,049	10/2001	Lee et al.			
	A38	6,346,195	02/2002	Filson et al.			
	A39	6,354,913	03/2002	Miyashita et al.			
	A40	6,367,486	04/2002	Lee et al.			
	A41	6,443,811	09/2002	Nojo et al.			
	A42	6,514,821	02/2003	Huang			
	A43	6,540,935	04/2003	Lee et al.			
	A44	6,561,876	05/2003	Tateyama et al.			
	A45	6,616,514	09/2003	Edelbach et al.			
	A46	SU2003/0124959	07/2003	Schoeder et al.			
	A47						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	B01	WO 01/02134	01/2001	PCT				
	B02	WO 01/14496	03/2001	PCT				
	B03	WO 99/64527	12/1999	PCT				
	B04	64-87146	03/1989	Japan				
	B05	1 118 647	07/2001	EPO				
	B06	1 104 778	06/2001	EPO				
	B07	1 036 836	09/2000	EPO				
	B08							

OTHER REFERENCES *(Including Author, Title, Date, Pertinent Pages, Etc.)*

	C01	"Slurry Engineering for Self-Stopping, Dishing Free SiO ₂ -CMP" by Nojo et al., IEEE, 1996 IEDM 96-349-352
	C02	
	C03	

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.